RECIPIENT
SPECIFICATIONS
MODEL: FC-13M
SPEC. No. : Q12-209-14B
DATE: Jan. 23. 2013
SEIKO EPSON CORPORATION 8548 Naka-minowa Minowa-machi Kamiina-gun Nagano-ken 399-4696 Japan
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PREPARED 7. Kurumigawa Takashi kurumizawa / TD·CS Quality Assurance Department Senior Staff

SPECIFICATIONS

1. Application

- 1) This document is applicable to the crystal unit that are delivered to ARIMA COMMUNICATION CORP. from Seiko Epson Corp.
- 2) This product complies with RoHS Directive.
- 3) This Product supplied (and any technical information furnished, if any) by Seiko Epson Corporation shall not be used for the development and manufacture of weapon of mass destruction or for other military purposes. Making available such products and technology to any third party who may use such products or technologies for the said purposes are also prohibited.
- 4) This product listed here is designed as components or parts for electronics equipment in general consumer use. We do not expect that any of these products would be incorporated or otherwise used as a component or part for the equipment, which requires an systems, and medical equipment, the functional purpose of which is to keep extra high reliability, such as satellite, rocket and other space life.
- 2. Product No. / Model

The product No. of this crystal clock oscillator's is X1A000031000100. The model is FC-13M.

3. Packing

It is subject to the packing standard of Seiko Epson Corp.

4. Warranty

Defective parts which originate with us are replaced free of charge in the case of defects being found with 12 months after delivery.

5. Amendment and/or termination

Amendment and/or termination of this specification is subject to the agreement between the two parties.

6. Contents

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[1] Absolute maximum ratings

			R	Rating value			
No.	Item	Symbol	Min.	Тур.	Max.	Unit	Note
1	Storage temperature range	T_stg	- 55		+ 125	°C	Suppose to be within CI STD at $+ 25 \text{ °C} \pm 3 \text{ °C}$.
2	Maximum level of drive	GL		0.5		μW	

[2] Operating range

			Ra	Rating value			
No.	Item	Symbol	Min.	Тур.	Max.	Unit	Note
1	Operating temperature range	T_use	- 40		+ 85	°C	
2	Level of drive	DL	0.01	0.1	0.5	μW	
3	Vibration mode		Fundamenta				

[3] Static characteristics

No.	Item		Symbol	Value	Unit	Conditions
1	Nominal Frequency	7	f_nom	32.768	kHz	
2	Frequency tolerance	e	f_tol	± 20	× 10 ⁻⁶	CL = 9 pF Ta = + 25 ± 3°C Level of drive : 0.1 μ W Not include aging
3	Motional resistance	;	R1	70 Max.	kΩ	
4	Motional capacitan	ce	C1	3.4 Тур.	fF	CI meter : Saunders 140B Level of drive : 0.5 µW
5	Shunt capacitance		C0	1.1 Typ.	pF	·
6	Frequency temperature	Turnover temperature	Ti	$+25\pm5$	°C	Values are calculated by The frequencies
0	characteristics	Parabolic coefficient	В	- 0.04 Max.	$\times 10^{-6} / {}^{\circ}C^{2}$	at $+ 10$, $+ 25$, $+ 40$ °C with C-MOS circuit.
7	Isolation resistance		IR	500 Min.	ΜΩ	DC 100V± 15, 60 seconds Between terminal # 1 and terminal # 2
8	Frequency Aging		f_age	± 3	\times 10 ⁻⁶ /year	Ta = $+25 \circ C \pm 3 \circ C$ Level of drive : 0.1 μ W

[4] Environmental and Mechanical characteristics

No.	Items	Value $[\times 10^{-6}] * 1 * 2$	Conditions
1	Shock resistance	*3 Δ f/f : ±15	 100 g dummy(Epson Toyocom Standard), Natural drop from 1500 mm height on to the concrete. 3 directions × 10 times
2	Vibration resistance	*3 $\Delta f/f$: ±3	10 Hz to 55 Hz amplitude 0.75 mm 55 Hz to 500 Hz acceleration 98 m/s ² 10 Hz \rightarrow 500 Hz \rightarrow 10 Hz 15 min./cycle 6 h (2 hours , 3 directions)
3	Soldering heat resistance	$\Delta f/f$: ±8	For convention reflow soldering furnace (3 times)
4	High temperature storage	*3 $\Delta f/f$: ±10	+ 125 °C × 1 000 h
		*3 $\Delta f/f$: ±7	+ 85 °C × 1 000 h
5	Low temperature storage	*3 $\Delta f/f$: ±15	- 55 °C × 1 000 h
6	High temperature and humidity	*3 $\Delta f/f$: ±10	+ 85°C × 85%RH × 1 000 h
7	Temperature cycle	*3 $\Delta f/f$: ±10	- 55 °C \leftrightarrow + 125 °C 30 minutes at each temperature × 100 cycles
8	Sealing	*3 1×10^{-8} hPa •1 / s Max.	For He leak detector
9	Shear	No peeling-off at a soldered part	20 N press for 10 ± 1 s. Ref. IEC 60068-2-21
10	Pull - off	No peeling-off at a soldered part	20 N press for 10 ± 1 s. Ref. IEC 60068-2-21
11	Substrate bending	No peeling-off at a soldered part	Bend width reaches 3 mm and hold for 5 s \pm 1 s \times 1 time Ref. IEC 60068-2-21
12	Solderability	More than 95 % covered by solder	Dip into methyl alcohol solution of rosin for 5 sec. at $+ 235 \pm 5 \text{ °C}$

< Notes >

*1 Each test done independently.

*2 Measuring 2 h to 24 h later leaving in room temperature after each test. Drive level : $0.5 \ \mu W$

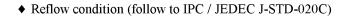
*3 Pre conditionings

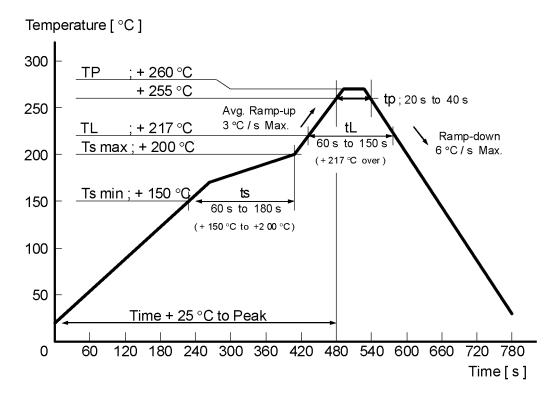
1. + 125 °C × 24 h to +85 °C × 85 %RH × 168 h \pm 1 h \rightarrow reflow 3 times

2. Initial value shall be after 24 h at room temperature.

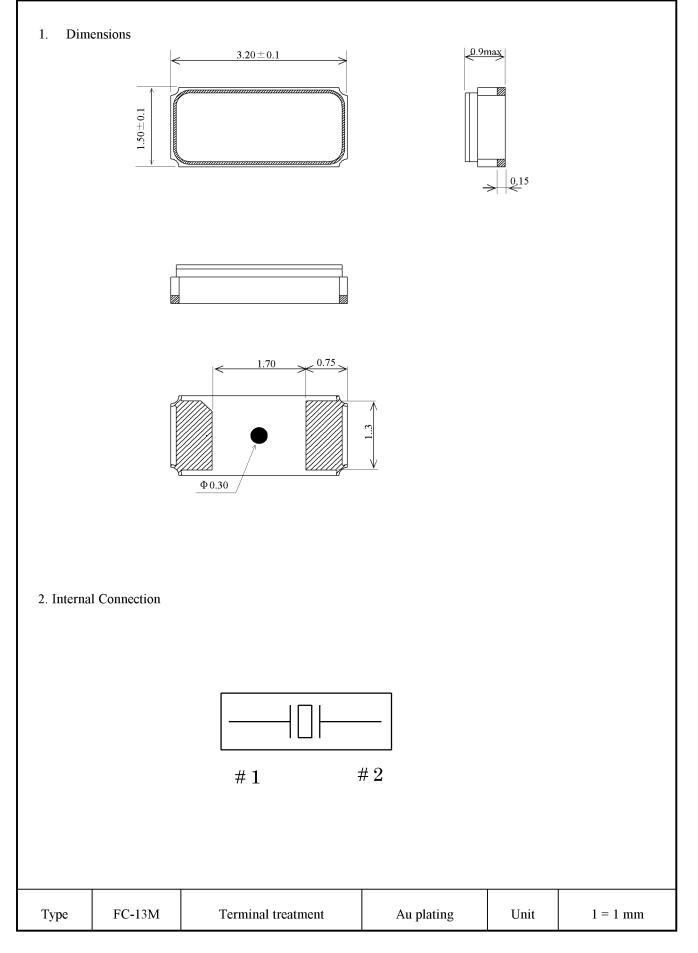
Shift of series resistance at before and after the test should be less than ± 30 % or less than ± 20 k Ω .

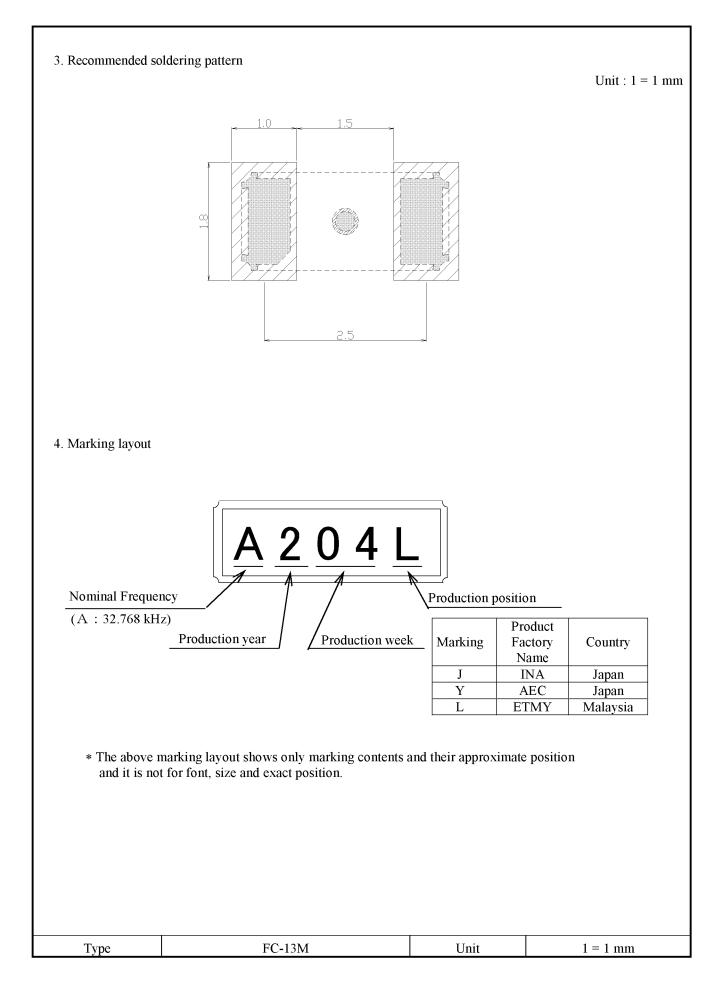
In case high temperature storage(+ 125 °C × 1 000 h), Soldering heat resistance, shift of series resistance at before and after the test should be less than \pm 40 % or \pm 30 k Ω .





[5] Dimensions and Marking layout

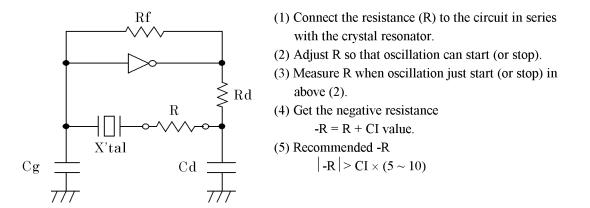




[6] Notes

- 1. Max three (3) times reflow is allowed. Once miss soldering is happened, hand work soldering by soldering iron is recommended. (+ $350 \text{ °C} \times \text{within 5 s}$)
- 2. Patterning should be followed by our recommended one.
- 3. Applying excessive excitation force to the crystal resonator may cause deterioration damage.
- 4. Unless adequate negative resistance is allocated in the oscillation circuit, start up time of oscillation may be increased, or no oscillation may occur.

How to check the negative resistance.



- 5. The shortest patterning line on board is recommendable. Too long line on board may cause of abnormal oscillation.
- 6. This device must be stored at the normal temperature and humidity conditions before mounting on a board.
- Too much exciting shock or vibration may cause deterioration on damage. Depending on the condition such as a shock in assembly machinery, the products may be damaged. Please check your condition in advance to maintain shock level to be smallest.
- 8. Depending on the conditions, ultrasonic cleaning may cause resonant damage of the internal crystal resonator. Since we are unable to determine the conditions (type of cleaning unit, power, time, conditions inside the bath, etc.) to be used in your company, we cannot guarantee the safety of this unit when it is cleaned in an ultrasonic cleaner.
- 9. Please refer to packing specification regarding how to storage the products in the pack.

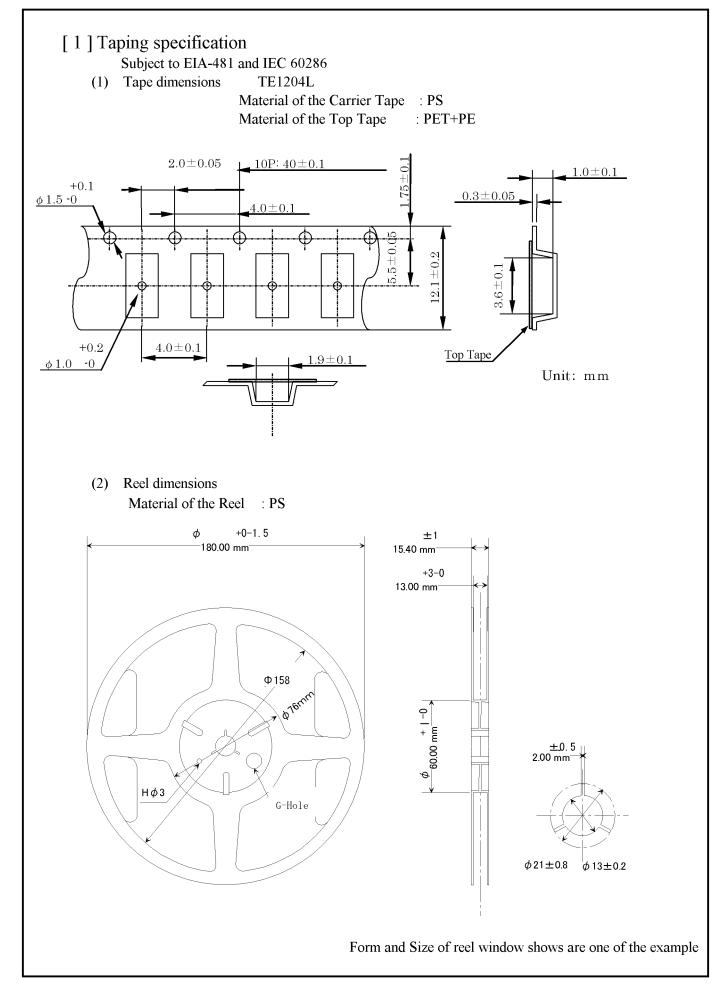
TAPING SPECIFICATION

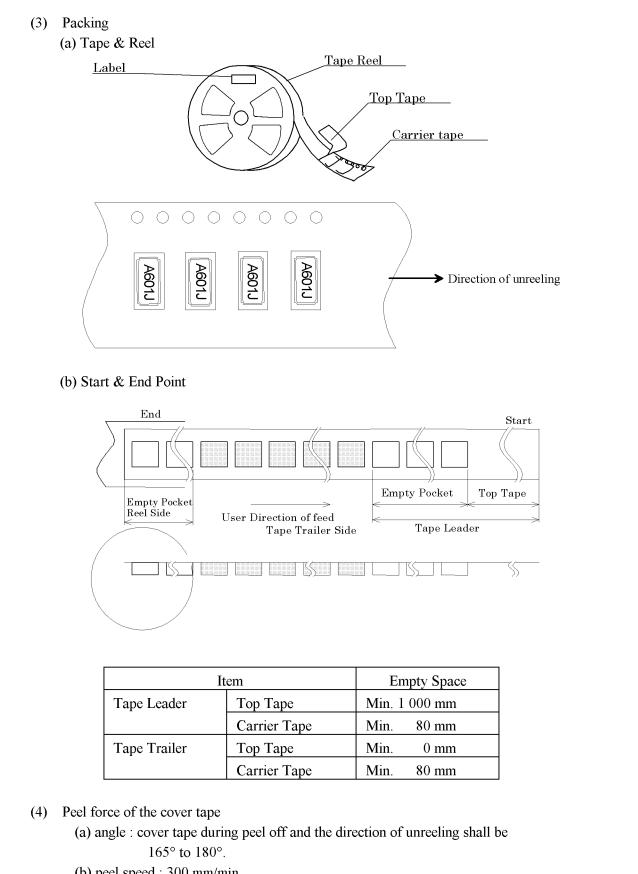
1. APPLICATION

This document is applicable to FC-13M.

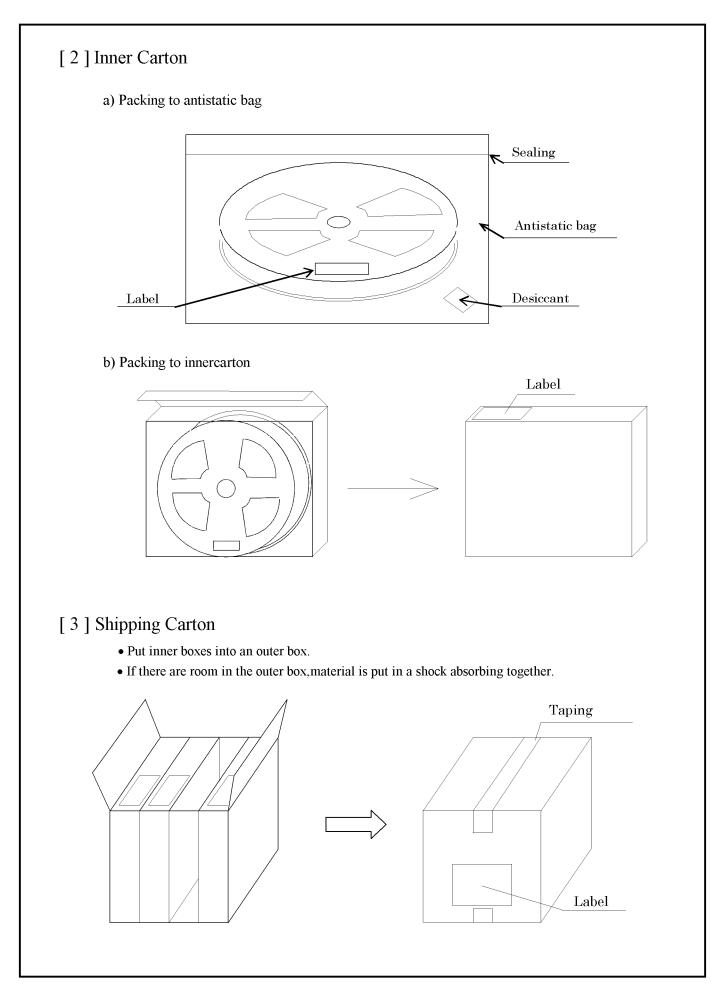
2. CONTENTS

Item No.	Item	Page
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[3]	Shipping carton	
[4]	Marking	4
[5]	Quantity	
[6]	Storage environment	
[7]	Handling	





(b) peel speed : 300 mm/min



[4] Marking

- (1) Reel marking
 - Reel marking shall consist of :
 - 1) Parts name
 - 2) Quantity
 - 3) Manufacturing Date or symbol
 - 4) Manufacturer's Date or symbol
 - 5) Others (if necessary)
- (2) Inner carton marking
 - Same as Reel marking.
- (3) Shipping carton marking
 - Shipping carton marking shall consist of :
 - 1) Parts name
 - 2) Quantity

[5] Quantity

• 3 000 pcs./reel

[6] Storage environment

- (1) To storage the reel at +15 °C to +35 °C, 25 %RH to 85 %RH of Humidity.
- (2) To open the packing just before using.
- (3) Not to expose the sun.
- (4) Not to storage with some erosive chemicals.
- (5) Nothing is allowed to put on the reel or carton to prevent mechanical damage.

[7] Handling

To handle with care to prevent the damage of tape, reel and products.

PROCESS QUALITY CONTROL

FC-13M No. C-0701-AIE-2

2009/3/9

Manufacturin	g process chart	No.	Section In Charge	Standard	Inspection Control Item	Inspection Methods	Instruments	Record
Crystal		1	Inspection Section	Purchasing Specification	Appearance	Sampling	Microscope	In-coming Inspection
			(INA Plant QA)	Incoming Inspection Standard	Dimension	Sampling	Tool Microscope	Data Sheet
ase,Lid 7	7	2	INA Plant	Manufacturing Instruction Sheet	Appearance	100% Inspection	Microscope	Process Data Sheet
∇	Ĺ	3	INA Plant	Manufacturing Instruction Sheet	Appearance	100% Inspection	Microscope	Process Data Sheet
	2 Crystal Setting	4	INA Plant	Manufacturing Instruction Sheet			_	
Inspection		5	INA Plant	Manufacturing Instruction Sheet	_		_	
Base (3) Mounting	6	INA Plant	Manufacturing Instruction Sheet	Frequency	100% Inspection	Frequency Adjustment Machine	Data Sheet
	ſ	7	INA Plant	Manufacturing Instruction Sheet	Appearance	100% Inspection	Microscope	Process Data Sheet
$\left \right \qquad \qquad$	US Cleaning	8	INA Plant	Manufacturing Instruction Sheet	Appearance	100% Inspection	Microscope	Process Data Sheet
		9	INA Plant	Manufacturing Instruction Sheet	Appearance	100% Inspection	Microscope	Process Data Sheet
	5 Annealing	10	INA Plant	Manufacturing Instruction Sheet	Frequency	100% Inspection	Characteristics In-	Process Data Sheet
					Crystal Impedance	100% Inspection	spection Machine	
(6) Frequency		1		Appearance	100% Inspection	Microscope	
	Adjustment	11	INA Plant	Specification Outgoing Inspection Standard	Electrical Characteristics	Sampling	Measuring Equipment	Outgoing Inspection
Lid(7 Lid Sealing				Appearance	Sampling	Microscope	Data Sheet
					Dimension	Sampling	Tool Microscope	
C		12	INA Plant	Packing Instruction	Customers	_	****	
	B Hermetic Sealing			Daily Shipping List	Туре	_		Shipping List
C	9) Marking	l	1		Quantity	-	_	
	⁹ Marking							
	0 Finish Products Inspection & Taping							
K	Outgoing Inspection							
	2 Packing							
Ship	ping							

PROCESS QUALITY CONTROL

FC-13M No. C-0701-AAE-1

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2009/3/9

Manufact	turing process chart	No.	Section In Charge	Standard	Inspection Control Item	Inspection Methods	Instruments	Record	
Crystal		1	Inspection Section	Purchasing Specification	Арреагалсе	Sampling	Microscope	In-coming Inspection	
Base,Lid	Crysial 5		(INA Plant QA)	Incoming Inspection Standard	Dimension	Sampling	Tool Microscope	Data Sheet	
Dase, Liu	Y	2	AKITA Plant	Manufacturing Instruction Sheet	Appearance	100% Inspection	Microscope	Process Data Sheet	
\bigtriangledown	2 Crystal Setting	3	AKITA Plant	Manufacturing Instruction Sheet	Appearance	100% Inspection	Microscope	Process Data Sheet	
In-coming Inspection		4	AKITA Plant	Manufacturing Instruction Sheet	_	_	_	_	
		5	AKITA Plant	Manufacturing Instruction Sheet		_	_	_	
Base	-3 Mounting	6	AKITA Plant	Manufacturing Instruction Sheet	Frequency	100% Inspection	Frequency Adjustment Machine	Data Sheet	
		7	AKITA Plant	Мапиfacturing Instruction Sheet	Appearance	100% Inspection	Microscope	Process Data Sheet	
	(4) US Cleaning	8	AKITA Plant	Manufacturing Instruction Sheet	Appearance	100% Inspection	Microscope	Process Data Sheet	
		9	AKITA Plant	Manufacturing Instruction Sheet	Appearance	100% Inspection	Microscope	Process Data Sheet	
	5 Annealing	10	AKITA Plant	Manufacturing Instruction Sheet	Frequency	100% Inspection	Characteristics In-		
					Crystal Impedance	100% Inspection	spection Machine	Process Data She	
	6 Frequency Adjustment			11 (11) (11) (11) (11) (11) (11) (11) (Appearance	100% Inspection	Microscope		
		11	AKITA Plant	ant Specification Outgoing Inspection Standard	Electrical Characteristics	Sampling	Measuring Equipment		
Lid —	-(7) Lid Sealing				Appearance	Sampling	Microscope	Outgoing Inspection	
			1		Dimension	Sampling	Tool Microscope	Dala chidot	
	(8) Hermetic Sealing	12	AKITA Plant	Packing Instruction Daily Shipping List	Customers	*****			
	\ominus				Туре	_		Shipping List	
	(9) Marking				Quantity				
	10 Finish Products Inspection & Taping 0utgoing Inspection 12 Packing								
	♦ Shipping								

PROCESS QUALITY CONTROL

FC-13M

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No. C-0701-AME-1

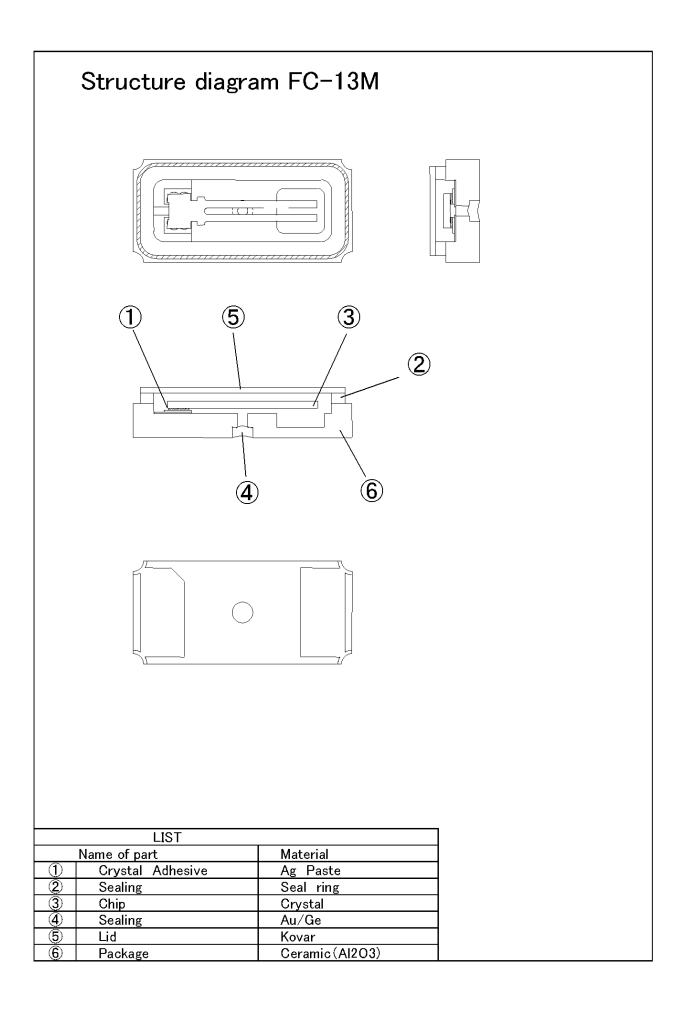
Manufacturing process chart No. Section In Charge Standard Inspection Control Item Inspection Methods Instruments Record 1 Inspection Section Purchasing Specification Appearance Sampling Microscope In-coming Inspection Crystal Data Sheet INA Plant QA) Incoming Inspection Standard Dimension Sampling Tool Microscope Base,Lid 2 MALAYSIA Plant 100% Inspection ∇ Manufacturing Instruction Sheet Appearance Microscope Process Data Sheet 3 MALAYSIA Plant Manufacturing Instruction Sheet Appearance 100% Inspection Microscope Process Data Sheet 2 Crystal Setting 4 MALAYSIA Plant Manufacturing Instruction Sheet _ — — In-coming 5 MALAYSIA Plant Manufacturing Instruction Sheet ------Inspection Frequency Adjustment 6 MALAYSIA Plant Manufacturing Instruction Sheet Frequency 100% Inspection Data Sheet Machine 3 Mounting Base 7 MALAYSIA Plant Manufacturing Instruction Sheet Microscope Appearance 100% Inspection Process Data Sheet 8 MALAYSIA Plant Manufacturing Instruction Sheet Appearance 100% Inspection Microscope Process Data Sheet 4 US Cleaning MALAYSIA Plant 9 Manufacturing Instruction Sheet 100% Inspection Appearance Microscope Process Data Sheet 10 MALAYSIA Plant Manufacturing Instruction Sheet Frequency 100% Inspection Characteristics In-5 Annealing spection Machine Process Data Sheet Crystal Impedance 100% Inspection Appearance 100% Inspection Microscope Frequency 6 MALAYSIA Plant 11 Specification Electrical Characteristics Adjustment Sampling Measuring Equipment Outgoing Inspection Outgoing Inspection Standard Appearance Sampling Microscope Data Sheet Lid 7 Lid Sealing Dimension Sampling Tool Microscope 12 MALAYSIA Plant Customers Packing Instruction ••••• — 8 Hermetic Sealing Daily Shipping List Type Shipping List ----_ Quantity _ _ 9 Marking Finish Products ´10` Inspection & Taping Kið

(12) Packing

Outgoing Inspection

Shipping

2009/3/9



RELIABILITY TEST DATA

Product Name : FC-13M J-STD-020C

The Company evaluation condition

We evaluate environmental and mechanical characteristics by the following test condition . F-C-0701-01-001J

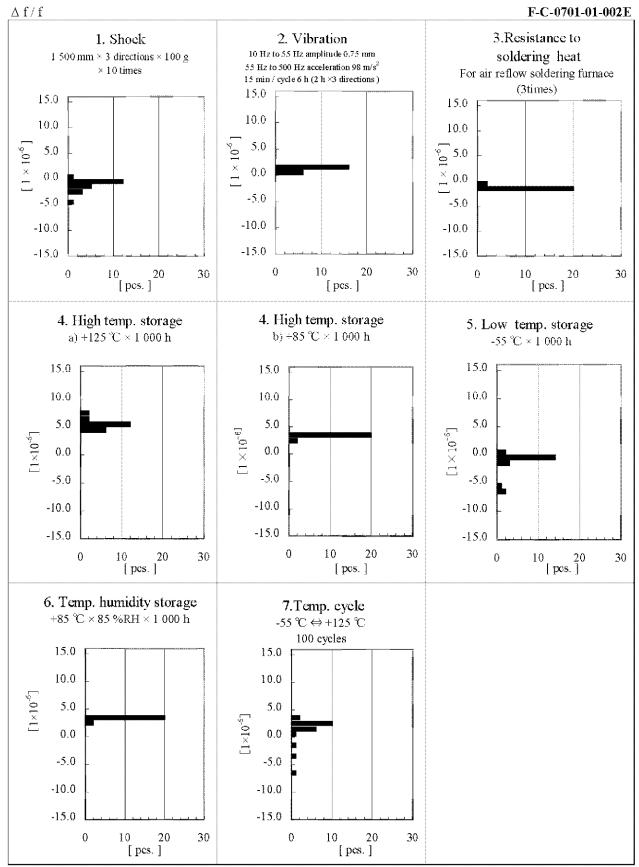
,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	valuate environmental	and mechanical characteristics by the followin	<u>×</u>	0/01-0.	1 0010
			VALUE *1 *2	TEST	FAIL
No.	ITEM	TEST CONDITIONS	$\Delta f / f$	Qty	Qty
			$[1 \times 10^{-6}]$	[n]	[n]
		100 g dummy (Epson Toyocom Standard)			
1	Shock	drop from 1 500 mm height on to the	*3 ± 15	22	0
		concrete 3 directions 10 times			
		10 Hz to 55 Hz amplitude 0.75 mm			
2	Vibration	55 Hz to 500 Hz acceleration 98 m/s^2	*3 ± 3	22	0
		$10 \text{ Hz} \rightarrow 500 \text{ Hz} \rightarrow 10 \text{ Hz}$ 15 min / cycle			
		$6 h (2 h \times 3 directions)$			
	Resistance to	For air reflow soldering furnace (3 times)			
3	soldering heat	Ref. J-STD-020C	± 8	22	0
	High temperature	a) +125°C × 1 000 h	*3 a) ± 10	a) 22	a) 0
4	storage				
		b) +85 °C × 1 000 h	*3 b) ± 7	b) 22	b) 0
	Low temperature				
5	storage	-55 °C × 1 000 h	*3 ± 15	22	0
	Temperature				
6	humidity storage	+85 °C × 85 %RH × 1 000 h	*3 ± 10	22	0
		$-55 \degree C \Leftrightarrow +125 \degree C$			
7	Temperature cycle	30 min at each temp. 100 cycles	$*3 \pm 10$	22	0
			0		
8	Sealing	For He leak detector	*3 1×10^{-8} hPa · 1 / s Max.	11	0
		20 N press for 10 s \pm 1 s	No peeling - off at a		
9	Shear	Ref. IEC 60068-2-21	solder part	11	0
		20 N press for 10 s \pm 1 s	No peeling - off at a		
10	Pull - off	Ref. IEC 60068-2-21	solder part	11	0
		Bend width reaches 3 mm and hold for	No peeling - off at a		
11	Substrate bending	$5 s \pm 1 s \times 1 time$	solder part	11	0
		Ref. IEC 60068-2-21			
	C 1				<u>^</u>
.12	Solvent resistance	Ref. JIS C 0052 or IEC 60068-2-45	I he marking shall be legible		0
12	Solvent resistance	Ref. JIS C 0052 or IEC 60068-2-45	The marking shall be legible	11	

Notes

*3 Pre conditionings(Treat the Reflow 3 times with the following profile) Initial value shall be after 24 h at room temperature. Shift of series resistance at before and after the test should be less than ±30 % or less than ±20 kΩ. In case high temperature storage(+125 °C × 1 000 h), Soldering heat resistance, shift of series resistance at before and after the test should be less than ±40 % or ±30 kΩ.

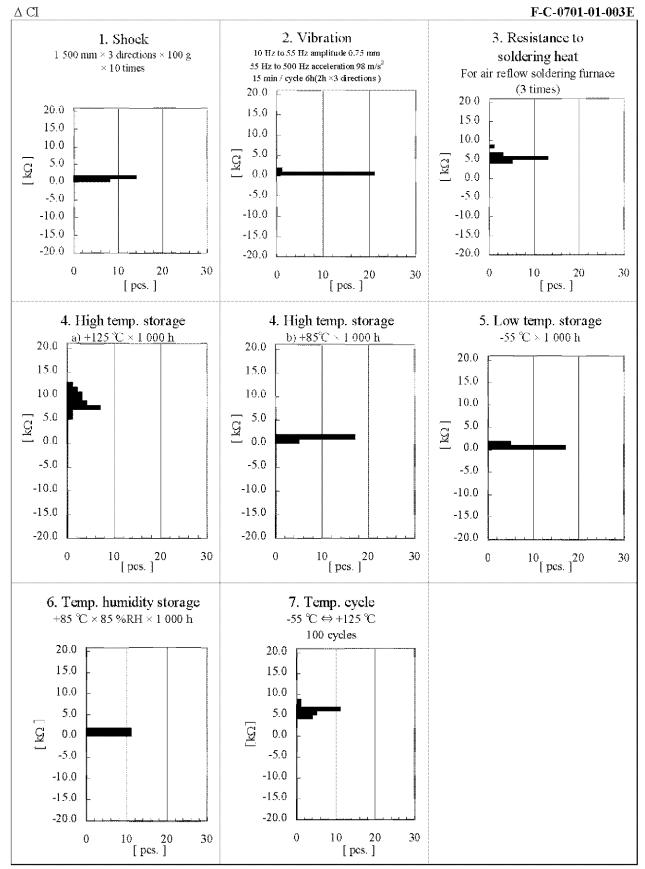
^{*1} Each test done independently.

^{*2} Measuring 2 h to 24 h later leaving in room temperature after each test. $DL:0.5\;\mu W$



Product Name : FC-13M J-STD-020C

Qualification Data



Product Name : FC-13M J-STD-020C

Qualification Data



To: ARIMA COMMUNICATION CORP.

No.ST12-514 Jan.23.2013

SEIKO EPSON CORPORATION TD-CS Quality Assurance Dept.

Product Name: FC-13M Subject: ESD and MSL

Thank you for choosing Seiko Epson Corp. as your Timing Device supplier. We would like to report our reply about above issue as below.

1)E.S.D ·Machine Model (C=200 pF;R=0 Ω)	: > ±300 Volt
·Human Body Model (C=100 pF;R=1 500 Ω)	: > ±1000 Volt

2) MSL FC-13M: MSL Level 1